

INFORMATION DISCLOSURE STATEMENT TRANSMITTAL

To Commissioner For Patents

Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.

Application Number	10/540068
Filing Date	
First Named Inventor	Johannes VAN WINGERDEN
Group Art Unit	
Examiner Name	
Atty. Docket Number	NL02 1489 US

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number (city ² -no. "kind", if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
/R.A./		US- 2002/085297	07-04-2002	VOWES STEVE WET AL	
↓		US- 6 272 392	08-07-2001	CAPODIECI LUIGI	
/R.A./		US- 6 478 484	11-12-2002	SINGH BHANWAR	
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number (city ² -no. "kind", if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	†
/R.A./		WO 01/84382	11-08-2001	KLA TENCOR INC.		
/R.A./		EP 1 271 246	01-02-2003	INFINEON TECHNOLOGIES		

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issu number(s), publisher, city and/or country where published.	†
/R.A./		NANAKLI S ET AL: "COMBINATION MULTIPLE FOCAL PLANES AND PSM FOR SUB 120 NM NODE WITH KIR LITHOGRAPHY: STUDY OF THE PROXIMITY EFFECTS" MICROELECTRONIC ENGINEERING, ELSEVIER PUBLISHERS BV, VOL. 61-62, JULY 2002, PAGES 123-132	
/R.A./		MACK C A ET AL: "DATA ANALYSIS FOR PHOTOLITHOGRAPHY" MICROELECTRONIC ENGINEERING, ELSEVIER PUBLISHERS BV, VOL. 64, NO. 1-4, MAY 1999, PAGES 65-68	

Examiner Signature	/Rashid Alam/	Date Considered	08/11/2008
--------------------	---------------	-----------------	------------

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.